1. Introduction

Internal friction or ultrasonic attenuation in solids is caused by the interaction of elastic stress-fields with elementary excitations in the solids such as phonons, electrons, magnons, lattice defects like dislocations, diffusion of interstitials and impurities, just to name a few [1]. In case of solids with a micro-, nano- or an amorphous structure, new paths are opened for the interaction with oscillatory stress-fields by scattering at grain boundaries and/or structural relaxation. In case the linear size of the microstructure becomes comparable to the wavelength employed or to the size of the stress field, additional effects occur. It is of special interest to study the interactions not only globally, but also locally, in order to learn more about the distribution of relaxation strengths in an amorphous structure. Here, we report data for a-SiO₂ as an extension of our earlier work for a-PdCuSi [2].

2. Atomic force microscopy – contact resonances

In atomic force microscopy a cantilever is employed as sensor. It exhibits many modes depending on its shape and geometrical dimensions. Their resonance frequencies cover a wide frequency spectrum extending into the ultrasonic frequency range also used for internal friction measurements. There are a number of atomic force techniques which combine the cantilever dynamics with ultrasonics, see for examples the collected papers in Ref. [3]. AFAM allows to measure the local indentation modulus M' by determining first the contact stiffness k∗ and then relating this quantity to M' using a suitable mechanical model. The modulus M' is an elastic constant which accounts for the compressive and the shear deformations in the tip-sample contact zone with the isotropic or anisotropic material [4]. Due to the damping of the oscillating cantilever, the contact stiffness k∗ = kₜ + ikᵢ becomes complex and hence the indentation modulus as well. For a circular contact this can be expressed as:

\[ k_\tau = 2a_c \times M' \]  
\[ k_\iota = 2a_c \times M'' \]  

where the complex indentation modulus is M = M' + iM'' and a_c is the contact radius. Because the cantilever is excited dynamically, viscoelastic damping yields for the imaginary part of the contact stiffness kᵢ = ωγ [5], where γ is the damping in the contact zone. Formally, the damping is represented by a dash-pot parallel to a spring which stands for the real part of the contact stiffness, k_τ. The local contact damping Q_{loc}⁻¹ is then given by
\[ Q_{\text{loc}}^{-1} = \frac{M''}{k} = \frac{\omega \gamma}{k} = \frac{M''}{M'}. \]  

Neither \( k \) nor \( k_r \) are directly measurable. The experimental quantities accessible are the resonance frequencies \( f_{\text{res}} \) and the Q-value of the contact resonance \( Q_{\text{res}}^{-1} = \Delta f_{\text{res}}/f_{\text{res}} \) where \( \Delta f_{\text{res}} \) is the width of the resonance curve. To what extent \( Q_{\text{loc}}^{-1} \) contributes to \( Q_{\text{res}}^{-1} \) is determined by the local velocity \( \partial y/\partial t \) of the cantilever at the tip position. How to evaluate the local indentation modulus and the local internal friction \( Q_{\text{loc}}^{-1} \) has been discussed in a number of recent papers, see for example [5, 6].

### 3. Experimental techniques

For the AFAM measurements, we used a Multimode AFM with a Nanoscope IV controller manufactured by Veeco-Metrology (now Bruker-Nano, S. Barbara, Ca.) and a commercial ultrasonic transducer (Panametrics V133-SM) with a center frequency of 2.25 MHz to excite the modes using the AFAM technique [2, 6]. In order to convert the measured contact stiffnesses into indentation moduli, calibration of the AFAM technique has to be undertaken [2]. Here, the mean value of the indentation modulus of the amorphous metallic glass PdCuSi was used as a calibration material. Measurements were taken in maps on 100 different positions in a squared lattice of \( 200 \times 200 \text{ nm}^2 \). Two maps were taken for amorphous SiO\(_2\) and from these maps corresponding statistics were derived. They were compared to data on the single crystal SrTiO\(_3\) which served as materials for comparison [2, 6]. For SrTiO\(_3\), the maximum of the distribution occurred at \( Q_{\text{loc}}^{-1} \approx 7.7 \times 10^{-3} \) and the distribution width was \( \Delta Q_{\text{loc}}^{-1} \approx 8 \times 10^{-4} \) and resulting in \( \Delta Q_{\text{loc}}^{-1}/Q_{\text{loc}}^{-1} \approx 0.15 \). For comparison, we made the same type of measurements on the single crystal (100)-SrTiO\(_3\) [2]. For SrTiO\(_3\), the maximum of the distribution occurred at \( Q_{\text{loc}}^{-1} \approx 6.4 \times 10^{-2} \) and a a distribution width of \( \Delta Q_{\text{loc}}^{-1} \approx 6 \times 10^{-3} \) (full width) and hence \( \Delta Q_{\text{loc}}^{-1}/Q_{\text{loc}}^{-1} \approx 0.15 \). For comparison, we made the same type of measurements on the single crystal (100)-SrTiO\(_3\) [2]. For SrTiO\(_3\), the maximum of the distribution occurred at \( Q_{\text{loc}}^{-1} \approx 7.7 \times 10^{-3} \) and the distribution width was \( \Delta Q_{\text{loc}}^{-1} \approx 8 \times 10^{-4} \) and resulting in \( \Delta Q_{\text{loc}}^{-1}/Q_{\text{loc}}^{-1} \approx 0.1 \).

### 4. Experimental results

Figure 1a shows the distribution of the indentation modulus \( M' \) in amorphous SiO\(_2\). The averaged value for all contact-resonance frequencies was \( f_{\text{cont}} = 1.678 \text{ MHz} \) and the resonance frequency of the free cantilever was \( f = 301 \text{ kHz} \). The difference between the maximal and the minimal frequency was 15 kHz. The shape of the curves was Lorentzian. From the measured contact-resonance frequencies, the contact stiffness was calculated [2]. It varied between 3140 - 3305 N/m which entails an indentation modulus \( M' \) of 47-52 GPa with an average value of 50 GPa. In the distribution of Fig. 1a, this corresponds to a variation of 2.9% relative to the average value. It is interesting to note that there is a tail in the distribution to lower moduli. For fused quartz, one expects an indentation modulus of 76 GPa [7]. Apparently, thermal oxidation of Si leads to an amorphous SiO\(_2\) layer with an elastic modulus reduced appreciably in comparison to fused quartz. Comparison experiments with nano-indentation were made for the metallic glass PdCuSi at the time at the time when experiments reported here and earlier [2] were carried out. They yielded the same results within measurement accuracy [2] and this holds also for other measurements made using AFAM [7-10]. Measurement accuracy below 10% can be obtained by careful calibration procedures [7-10].

The influence of the surface roughness on the distribution of the indentation modulus of a-PdCuSi has been discussed in the supplementary information of Ref. [2] and it turned out to be negligible for our measurements. The conditions for the measurements on SiO\(_2\) were the same [11] and we are confident that the interpretation of our data cannot be explained by surface roughness effects. If there are larger variations in surface roughness, it is possible to deconvolute the data in respect to surface roughness [9].

The variations in \( \Delta M'/M' \) can be viewed as a spatially varying modulus defect. Therefore a corresponding variation must be seen in the internal friction as well. Based on the evaluation procedure discussed in [6], Fig. 1b shows the distribution of the local damping for amorphous SiO\(_2\) with the maximum at \( Q_{\text{loc}}^{-1} \approx 4.1 \times 10^{-2} \) and a distribution width of \( \Delta Q_{\text{loc}}^{-1} \approx 6 \times 10^{-3} \) (full width) and hence \( \Delta Q_{\text{loc}}^{-1}/Q_{\text{loc}}^{-1} \approx 0.15 \). For comparison, we made the same type of measurements on the single crystal (100)-SrTiO\(_3\) [2]. For SrTiO\(_3\), the maximum of the distribution occurred at \( Q_{\text{loc}}^{-1} \approx 7.7 \times 10^{-3} \) and the distribution width was \( \Delta Q_{\text{loc}}^{-1} \approx 8 \times 10^{-4} \) and resulting in \( \Delta Q_{\text{loc}}^{-1}/Q_{\text{loc}}^{-1} \approx 0.1 \).

**Fig. 1.** (a): Statistics of the measured indentation modulus on amorphous SiO\(_2\) comprising 200 measuring points. (b): Distribution of internal friction \( Q_{\text{loc}}^{-1} \) for amorphous SiO\(_2\). Measurements were taken in two maps on 100 different positions in a squared lattice of \( 200 \times 200 \text{ nm}^2 \) size.

### 5. Discussion

The variation of AFAM contact-resonance frequencies and hence the local elasticity and local damping of amorphous SiO\(_2\) can be explained in the context of local atomic configuration and atomic-level stress. In disordered materials, there exist large local stresses and prohibit a unique glassy or liquid ground state. Amorphous materials arrange in a large manifold of configurations, in which local stresses vary significantly on the nm-scale [12]. This manifests itself in a potential energy landscape (PEL) which represents in 3N-dimensions a wide variety of metabasins for the amorphous structure in contrast to a single crystalline ground state [12-14]. Each individual metabasin represents a local configuration and can be characterized by its local shear modulus [15]. In other words, there exists a spatially varying relative local modulus \( \Delta M'/M' \) and a locally varying internal friction. These effects have been found in the metallic glass PdCuSi as well [2, 6], however, not in the polycrystalline counterpart PdCuSi or the single crystal SrTiO\(_3\) which served as materials for comparison [2, 6].

Here, we probe such a structural excitation and/or relaxation locally in Q\(^{-1}\). We observed the same distribution of quantitative...
local internal friction as was observed in $\Delta k/k$, or in $\Delta M'/M'$ . Because internal friction by structural relaxation is observed at a subset of metabasins of the potential energy landscape, there exists a locally varying average of relaxation times, which eventually leads to a spatially varying internal friction which we observe here. Recently, combined inelastic X-ray scattering and ultrasonic measurements have revealed that there must be an intrinsic nanoscale inhomogeneity in elasticity [16], which agrees with our arguments presented here.

As in the real part of the modulus, the imaginary part of the modulus is most interesting. This will be explored further in a set of measurements of the local modulus and of the local damping is also reduced. compared to the metallic glass. Therefore, the distribution of local configurations is limited than expected. Since we deal here with a so-called oxide network glass, the distribution of local configurations is limited. In comparison to the metallic glass PdCuSi [2], the distribution in $\Delta M'/M'$ and in $Q^{-1}$ [6] is significantly smaller than expected. Since we deal here with a so-called oxide network glass, the distribution of local configurations is limited compared to the metallic glass. Therefore, the distribution of the local modulus and of the local damping is also reduced. This will be explored further in a set of measurements of “fragile” and “strong” glass forming systems.

6. Summary

We demonstrate here a quantitative way to determine the local internal friction or loss on a nanometer scale by using the AFAM-technique. The evaluation of the data is based on the cantilever’s mass distribution with damped flexural modes. The width of the distribution changes from the amorphous to the crystalline case as expected from the consequences of the potential energy landscape picture. This is compared to $Q^{-1}$ measured in crystalline SrTiO$_3$, which exhibits a narrow distribution, as expected. Future work will concentrate on other amorphous versus crystalline systems like polymers and biopolymers, where the local information on the real and imaginary part of the modulus is most interesting.

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